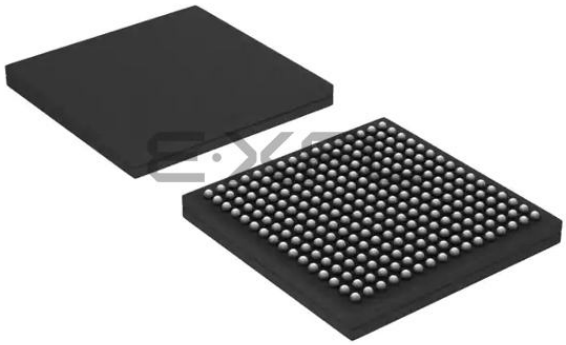

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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	Coldfire V2
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, SPI, UART/USART
Peripherals	DMA, WDT
Number of I/O	97
Program Memory Size	-
Program Memory Type	ROMless
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	1.4V ~ 1.6V
Data Converters	-
Oscillator Type	External
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	256-LBGA
Supplier Device Package	256-MAPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mcf5234cvm100

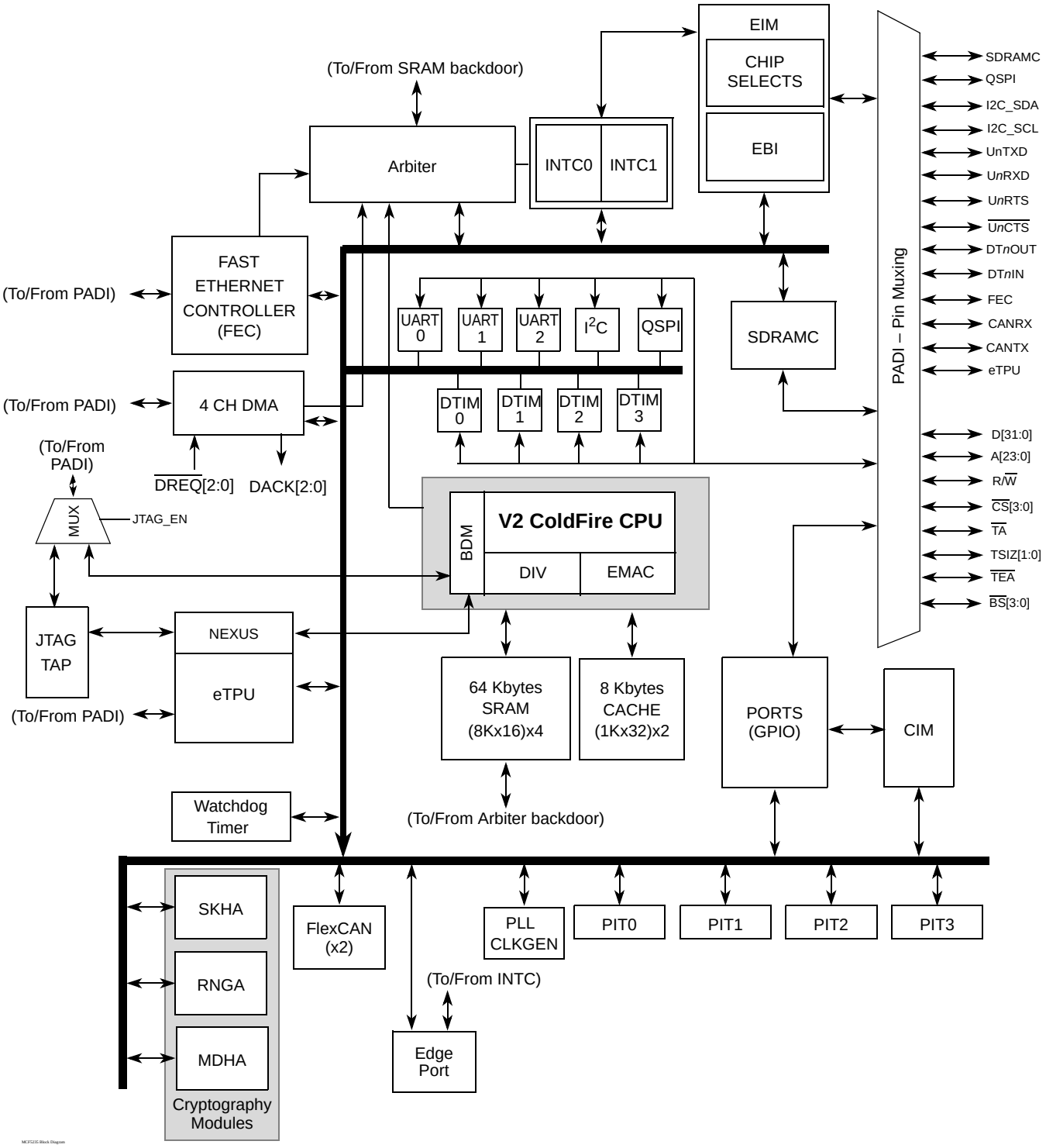
1 MCF523*x* Family Configurations

Table 1. MCF523*x* Family Configurations

Module	MCF5232	MCF5233	MCF5234	MCF5235
ColdFire V2 Core with EMAC (Enhanced Multiply-Accumulate Unit)	x	x	x	x
Enhanced Time Processor Unit with memory (eTPU)	16-ch 6K	32-ch 6K	16-ch 6K	32-ch 6K
System Clock	up to 150 MHz			
Performance (Dhrystone/2.1 MIPS)	up to 144			
Instruction/Data Cache	8 Kbytes			
Static RAM (SRAM)	64 Kbytes			
Interrupt Controllers (INTC)	2	2	2	2
Edge Port Module (EPORT)	x	x	x	x
External Interface Module (EIM)	x	x	x	x
4-channel Direct-Memory Access (DMA)	x	x	x	x
SDRAM Controller	x	x	x	x
Fast Ethernet Controller (FEC)	—	—	x	x
Cryptography - Security module for data packets processing	—	—	—	x
Watchdog Timer (WDT)	x	x	x	x
Four Periodic Interrupt Timers (PIT)	x	x	x	x
32-bit DMA Timers	4	4	4	4
QSPI	x	x	x	x
UART(s)	3	3	3	3
I^2C	x	x	x	x
FlexCAN 2.0B - Controller-Area Network communication module	1	2	1	2
General Purpose I/O Module (GPIO)	x	x	x	x
JTAG - IEEE 1149.1 Test Access Port	x	x	x	x
Package	160 QFP 196 MAPBGA	256 MAPBGA	256 MAPBGA	256 MAPBGA

2 Block Diagram

The superset device in the MCF523*x* family comes in a 256 mold array process ball grid array (MAPBGA) package. Figure shows a top-level block diagram of the MCF5235, the superset device.



3 Features

For a detailed feature list see the MCF5235 Reference Manual (MCF5235RM).

Table 2. MCF523x Signal Information and Muxing (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Dir.[1]	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA
A[20:0]	—	—	—	O	123:115, 112:106, 102:98	A12, B12, C12, A13, B13, B14, C13, C14, D12, D13, D14, E11, E12, E13, E14, F12, F13, F14, G11, G12, G13	B15, B16, C15, C16, D16, D15, D14, E16, E15, E14, E13, F15, F14, F13, G15, G14, G13, H16, H15, H14, H13	B15, B16, C15, C16, D16, D15, D14, E16, E15, E14, E13, F15, F14, F13, G15, G14, G13, H16, H15, H14, H13	B15, B16, C15, C16, D16, D15, D14, E16, E15, E14, E13, F15, F14, F13, G15, G14, G13, H16, H15, H14, H13
D[31:16]	—	—	—	O	21:24, 26:30, 33:39	G1, G2, H1, H2, H3, H4, J1, J2, J3, J4, K1, K2, K3, K4, L1, L2	K4, K3, K2, K1, L4, L3, L2, L1, M3, M2, M1, N2, N1, P2, P1, R1	K4, K3, K2, K1, L4, L3, L2, L1, M3, M2, M1, N2, N1, P2, P1, R1	K4, K3, K2, K1, L4, L3, L2, L1, M3, M2, M1, N2, N1, P2, P1, R1
D[15:8]	PDATAH[7:0]	—	—	O	42:49,	M1, N1, M2, N2, P2, L3, M3, N3,	R2, T2, N3, P3, R3, T3, N4, P4,	R2, T2, N3, P3, R3, T3, N4, P4,	R2, T2, N3, P3, R3, T3, N4, P4,
D[7:0]	PDATAL[7:0]	—	—	O	50:52, 56:60	P3, M4, N4, P4, L5, M5, N5, P5	R4, T4, P5, R5, N6, P6, R6, N7	R4, T4, P5, R5, N6, P6, R6, N7	R4, T4, P5, R5, N6, P6, R6, N7
$\overline{BS}$[3:0]	PBS[7:4]	$\overline{CAS}$[3:0]	—	O	143:140	B6, C6, D7, C7	C9, B9, A9, A10	C9, B9, A9, A10	C9, B9, A9, A10
$\overline{OE}$	PBUSCTL7	—	—	O	63	N6	T7	T7	T7
$\overline{TA}$	PBUSCTL6	—	—	I	97	H11	K14	K14	K14
$\overline{TEA}$	PBUSCTL5	$\overline{DREQ1}$	—	I	—	J14	K13	K13	K13
R/$\overline{W}$	PBUSCTL4	—	—	O	96	J13	L16	L16	L16
$\overline{TSIZ1}$	PBUSCTL3	DACK1	—	O	—	P6	N8	N8	N8
$\overline{TSIZ0}$	PBUSCTL2	DACK0	—	O	—	P7	P8	P8	P8
$\overline{TS}$	PBUSCTL1	DACK2	—	O	—	H13	K16	K16	K16
$\overline{TIP}$	PBUSCTL0	$\overline{DREQ0}$	—	O	—	H12	K15	K15	K15
Chip Selects									
$\overline{CS}$[7:4]	PCS[7:4]	—	—	O	—	B9, A10, C10, A11	C12, A13, C13, A14	C12, A13, C13, A14	C12, A13, C13, A14
$\overline{CS}$[3:2]	PCS[3:2]	SD_CS[1:0]	—	O	134,133	A9, C9	B12, D12	B12, D12	B12, D12
$\overline{CS1}$	PCS1	—	—	O	130	B10	B13	B13	B13
$\overline{CS0}$	—	—	—	O	129	D10	D13	D13	D13
SDRAM Controller									

Table 2. MCF523x Signal Information and Muxing (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Dir.[1]	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA
ECRS	—	—	—	I	—	—	—	F4	F4
ERXCLK	—	—	—	I	—	—	—	E3	E3
ERXDV	—	—	—	I	—	—	—	E4	E4
ERXD[3:0]	—	—	—	I	—	—	—	D3, D4, C3, C4	D3, D4, C3, C4
ERXER	—	—	—	I	—	—	—	D5	D5
ETXCLK	—	—	—	I	—	—	—	C5	C5
ETXEN	—	—	—	O	—	—	—	D6	D6
ETXER	—	—	—	O	—	—	—	C6	C6
ETXD[3:0]	—	—	—	O	—	—	—	B6, B5, A5, B7	B6, B5, A5, B7
Feature Control									
eTPU/$\overline{\text{EthENB}}$	—	—	—	I	—	—	—	—	M4
I^2C									
I2C_SDA	PFECI2C1	CAN0RX	—	I/O	—	J12	L15	L15	L15
I2C_SCL	PFECI2C0	CAN0TX	—	I/O	—	J11	L14	L14	L14
DMA									
DACK[2:0] and $\overline{\text{DREQ}}$[2:0] do not have a dedicated bond pads. Please refer to the following pins for muxing: $\overline{\text{TS}}$ and DT2OUT for DACK2, TSIZ1and DT1OUT for $\overline{\text{DACK1}}$, TSIZ0 and DT0OUT for $\overline{\text{DACK0}}$, $\overline{\text{IRQ2}}$ and DT2IN for $\overline{\text{DREQ2}}$, $\overline{\text{TEA}}$ and DT1IN for $\overline{\text{DREQ1}}$, and $\overline{\text{TIP}}$ and DT0IN for $\overline{\text{DREQ0}}$.					—	—	—	—	—
QSPI									
QSPI_CS1	PQSPI4	SD_CKE	—	O	139	B7	B10	B10	B10
QSPI_CS0	PQSPI3	—	—	O	147	A6	D9	D9	D9
QSPI_CLK	PQSPI2	I2C_SCL	—	O	148	C5	B8	B8	B8
QSPI_DIN	PQSPI1	I2C_SDA	—	I	149	B5	C8	C8	C8
QSPI_DOUT	PQSPI0	—	—	O	150	A5	D8	D8	D8
UARTs									
U2TXD	PUARTH1	CAN1TX	—	O	—	A8	D11	D11	D11
U2RXD	PUARTH0	CAN1RX	—	I	—	A7	D10	D10	D10
$\overline{\text{U1CTS}}$	PUARTL7	$\overline{\text{U2CTS}}$	—	I	—	B8	C11	C11	C11
$\overline{\text{U1RTS}}$	PUARTL6	$\overline{\text{U2RTS}}$	—	O	—	C8	B11	B11	B11
U1TXD	PUARTL5	CAN0TX	—	O	135	D9	A12	A12	A12

Table 2. MCF523x Signal Information and Muxing (continued)

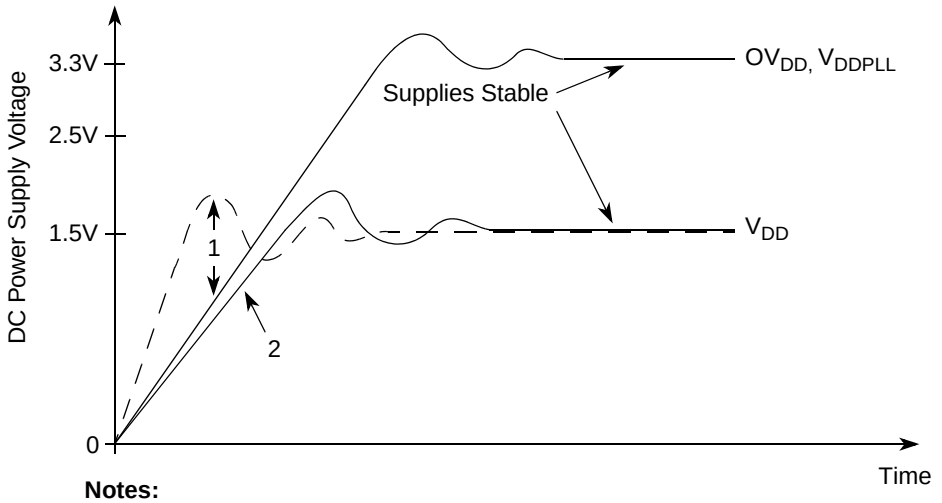
Signal Name	GPIO	Alternate 1	Alternate 2	Dir.[1]	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA
U1RXD	PUARTL4	CAN0RX	—	I	136	D8	A11	A11	A11
$\overline{\text{U0CTS}}$	PUARTL3	—	—	I	—	F3	G1	G1	G1
$\overline{\text{U0RTS}}$	PUARTL2	—	—	O	—	G3	H3	H3	H3
U0TXD	PUARTL1	—	—	O	14	F1	H2	H2	H2
U0RXD	PUARTL0	—	—	I	13	F2	G2	G2	G2
DMA Timers									
DT3IN	PTIMER7	$\overline{\text{U2CTS}}$	QSPI_CS2	I	—	H14	J15	J15	J15
DT3OUT	PTIMER6	$\overline{\text{U2RTS}}$	QSPI_CS3	O	—	G14	J16	J16	J16
DT2IN	PTIMER5	$\overline{\text{DREQ2}}$	DT2OUT	I	—	M9	P10	P10	P10
DT2OUT	PTIMER4	DACK2	—	O	—	L9	R10	R10	R10
DT1IN	PTIMER3	$\overline{\text{DREQ1}}$	DT1OUT	I	—	L6	P7	P7	P7
DT1OUT	PTIMER2	DACK1	—	O	—	M6	R7	R7	R7
DT0IN	PTIMER1	$\overline{\text{DREQ0}}$	—	I	—	E4	G4	G4	G4
DT0OUT	PTIMER0	DACK0	—	O	—	F4	G3	G3	G3
BDM/JTAG[2]									
DSCLK	—	TRST	—	I	70	N9	N11	N11	N11
PSTCLK	—	TCLK	—	O	68	P9	T10	T10	T10
$\overline{\text{BKPT}}$	—	TMS	—	I	71	P10	P11	P11	P11
DSI	—	TDI	—	I	73	M10	T11	T11	T11
DSO	—	TDO	—	O	72	N10	R11	R11	R11
JTAG_EN	—	—	—	I	78	K9	N13	N13	N13
DDATA[3:0]	—	—	—	O	—	M12, N12, P12, L11	N14, P14, T13, R13	N14, P14, T13, R13	N14, P14, T13, R13
PST[3:0]	—	—	—	O	77:74	M11, N11, P11, L10	T12, R12, P12, N12	T12, R12, P12, N12	T12, R12, P12, N12

5.2 Power Supply

- 33 μF, 0.1 μF, and 0.01 μF across each power supply

5.2.1 Supply Voltage Sequencing and Separation Cautions

Figure 1 shows situations in sequencing the I/O V_{DD} (OV_{DD}), PLL V_{DD} (V_{DDPLL}), and Core V_{DD} (V_{DD}). OV_{DD} is specified relative to V_{DD}.



Notes:
1. VDD should not exceed OVDD or VDDPLL by more than 0.4 V at any time, including power-up.
2. Recommended that VDD should track OVDD/VDDPLL up to 0.9 V, then separate for completion of ramps.
3. Input voltage must not be greater than the supply voltage (OVDD, VDD, or VDDPLL) by more than 0.5 V at any time, including during power-up.
4. Use 1 ms or slower rise time for all supplies.

Figure 1. Supply Voltage Sequencing and Separation Cautions

5.2.1.1 Power Up Sequence

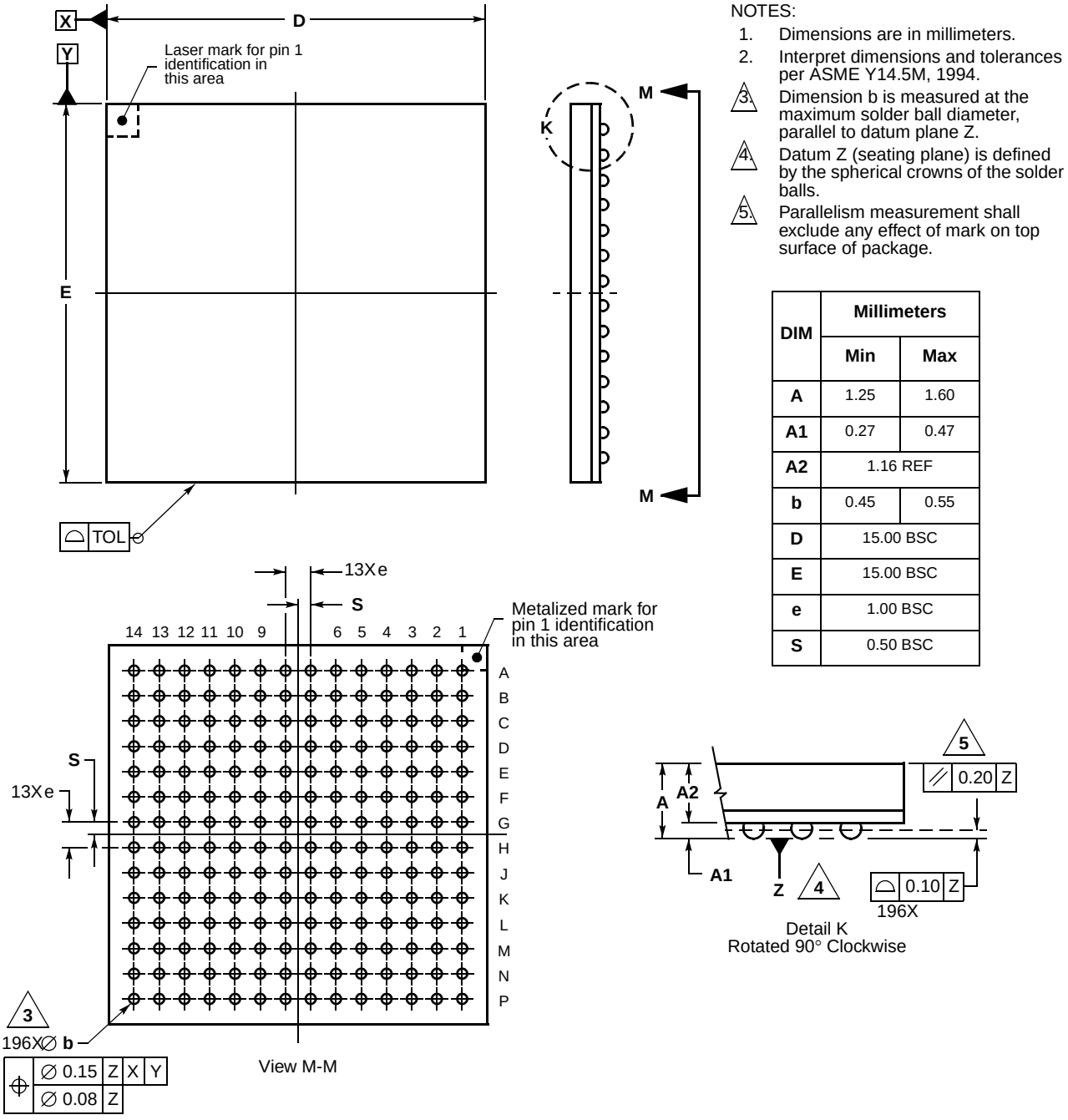
If OV_{DD} is powered up with V_{DD} at 0 V, then the sense circuits in the I/O pads cause all pad output drivers connected to the OV_{DD} to be in a high impedance state. There is no limit on how long after OV_{DD} powers up before V_{DD} must power up. V_{DD} should not lead the OV_{DD} or V_{DDPLL} by more than 0.4 V during power ramp-up, or there will be high current in the internal ESD protection diodes. The rise times on the power supplies should be slower than 1 μs to avoid turning on the internal ESD protection clamp diodes.

The recommended power up sequence is as follows:

1. Use 1 ms or slower rise time for all supplies.
2. V_{DD} and OV_{DD}/V_{DDPLL} should track up to 0.9 V, then separate for the completion of ramps with OV_{DD} going to the higher external voltages. One way to accomplish this is to use a low drop-out voltage regulator.

6.2 Package Dimensions—196 MAPBGA

Figure 3 shows MCF5232CVMxxx package dimensions.



NOTES:
1. Dimensions are in millimeters.
2. Interpret dimensions and tolerances per ASME Y14.5M, 1994.
3. Dimension b is measured at the maximum solder ball diameter, parallel to datum plane Z.
4. Datum Z (seating plane) is defined by the spherical crowns of the solder balls.
5. Parallelism measurement shall exclude any effect of mark on top surface of package.

DIM	Millimeters	
	Min	Max
A	1.25	1.60
A1	0.27	0.47
A2	1.16 REF	
b	0.45	0.55
D	15.00 BSC	
E	15.00 BSC	
e	1.00 BSC	
S	0.50 BSC	

Figure 3. 196 MAPBGA Package Dimensions (Case No. 1128A-01)

6.2.1 Pinout—256 MAPBGA

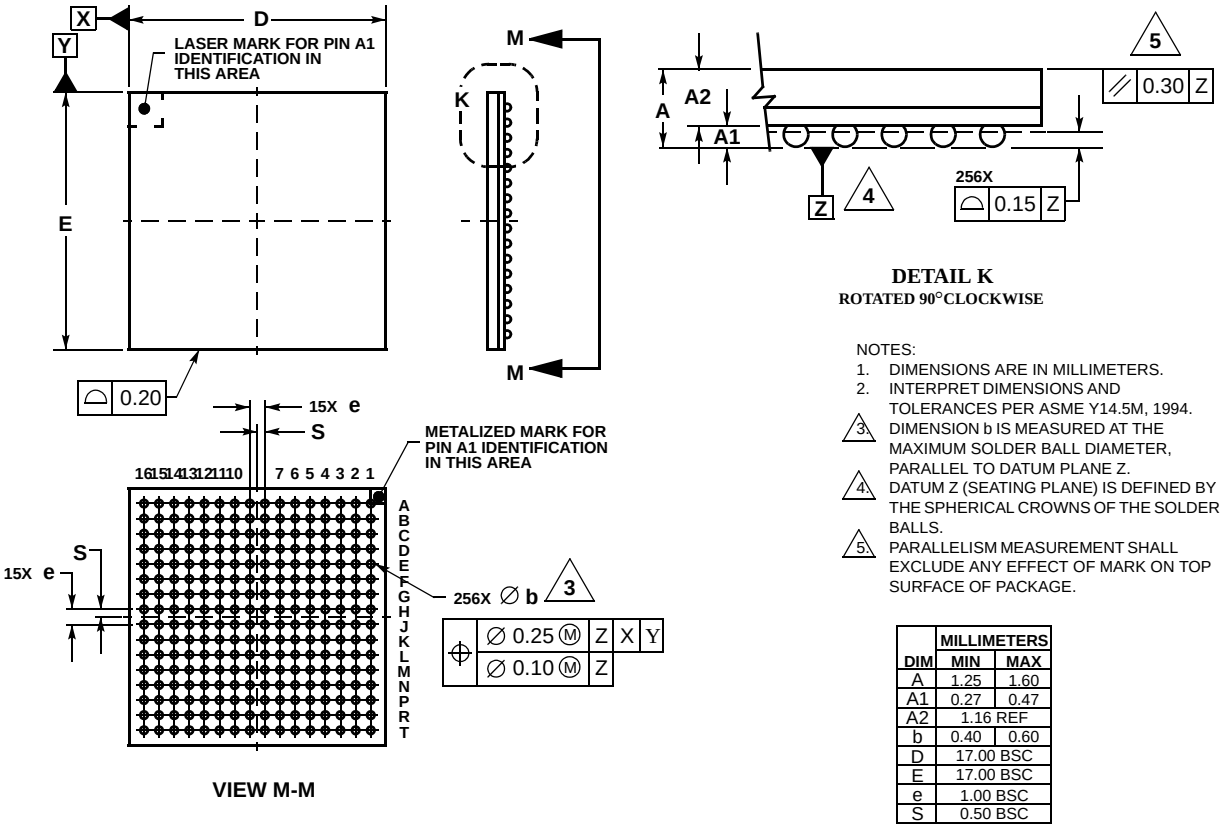
Figure 4 through Figure 6 show pinouts of the MCF5233CVMxxx, MCF5234CVMxxx, and MCF5235CVMxxx packages.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
A	VSS	TPUCH6	TPUCH4	TPUCH2	TPUCH17	TPUCH1	TPUCH0	VDD	BS1	BS0	U1RXD/ CAN0RX	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	A
B	TPUCH8	TPUCH7	TPUCH5	TPUCH3	TPUCH18	TPUCH19	TPUCH16	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	B
C	TPUCH10	TPUCH9	TPUCH25	TPUCH24	TPUCH22	TPUCH20	I2C_SDA/ U2RXD	QSPI_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	C
D	TPUCH12	TPUCH11	TPUCH27	TPUCH26	TPUCH23	TPUCH21	I2C_SCL/ U2TXD	QSPI_ DOUT	QSPI_ CS0	U2RXD/ CAN1RX	U2TXD/ CAN1TX	CS2	CS0	A14	A15	A16	D
E	TPUCH14	TPUCH13	TPUCH29	TPUCH28	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	A10	A11	A12	A13	E
F	TCRCLK	TPUCH15	TPUCH31	TPUCH30	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	A7	A8	A9	VSS	F
G	U0CTS	U0RXD	DT0OUT	DT0IN	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A4	A5	A6	VDD	G
H	VDD	U0TXD	U0RTS	NC	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A0	A1	A2	A3	H
J	VSS	CLK MOD0	CLK MOD1	TEST	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	D28	D29	D30	D31	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	TEA	TA	TIP	TS	K
L	D24	D25	D26	D27	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SDA/ CAN0RX	R/W	L
M	D21	D22	D23	NC	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	SD_ CS0	SD_ SRAS	SD_ SCAS	CLKOUT	M
N	D19	D20	D13	D9	NC	D3	D0	TSIZ1	IRQ5	IRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N
P	D17	D18	D12	D8	D5	D2	DT1IN	TSIZ0	IRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	P
R	D16	D15	D11	D7	D4	D1	DT1OUT	IRQ7	IRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
T	VSS	D14	D10	D6	VDD	VSS	OE	IRQ6	IRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RSTOUT	RESET	VSS	T
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 4. MCF5233CVMxxx Pinout (256 MAPBGA)

6.2.2 Package Dimensions—256 MAPBGA

Figure 7 shows MCF5235CVMxxx, MCF5234CVMxxx, and MCF5233CVMxx package dimensions.



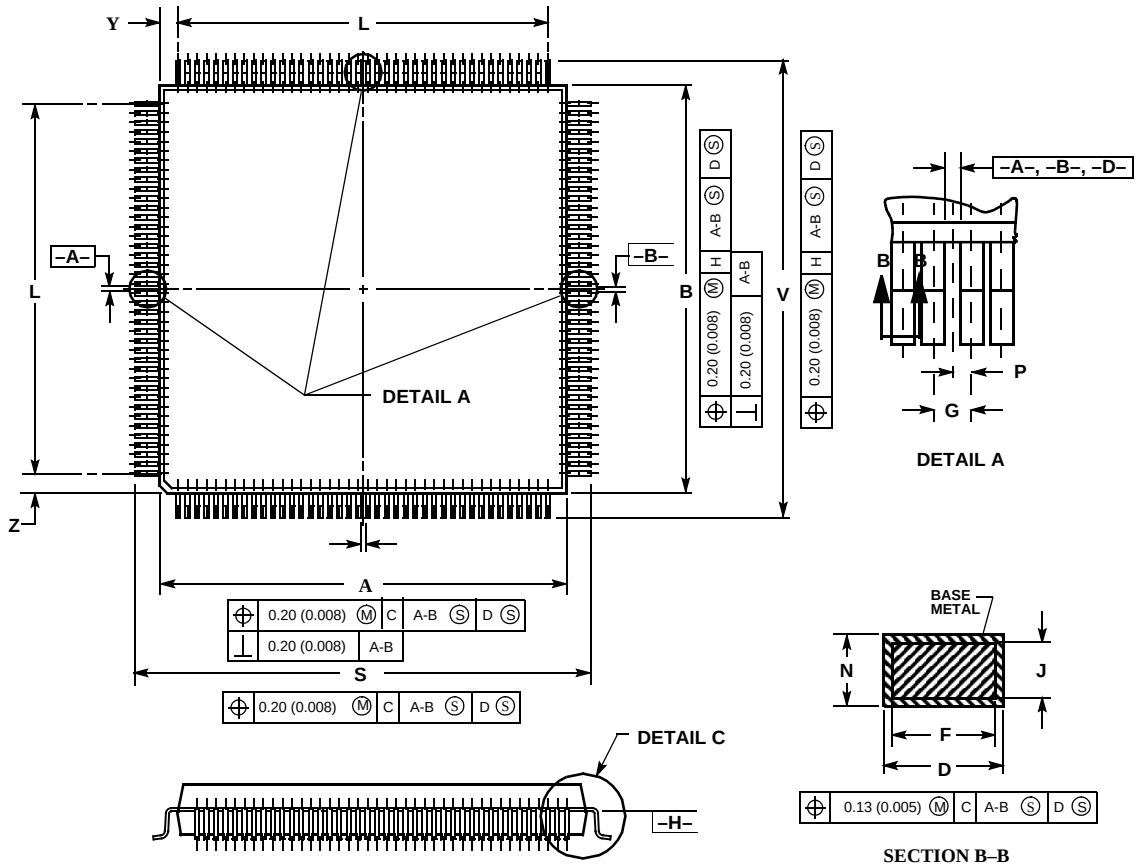
NOTES:
1. DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
3. DIMENSION b IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER, PARALLEL TO DATUM PLANE Z.
4. DATUM Z (SEATING PLANE) IS DEFINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PARALLELISM MEASUREMENT SHALL EXCLUDE ANY EFFECT OF MARK ON TOP SURFACE OF PACKAGE.

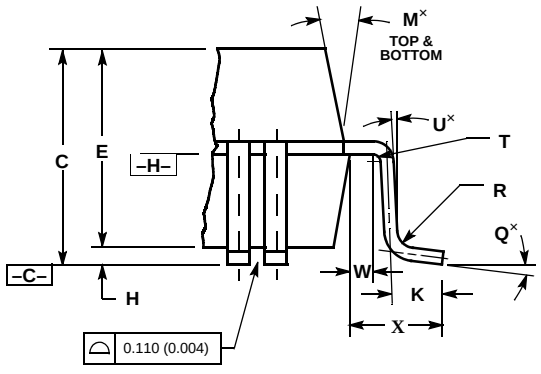
	MILLIMETERS	
DIM	MIN	MAX
A	1.25	1.60
A1	0.27	0.47
A2	1.16 REF	
b	0.40	0.60
D	17.00 BSC	
E	17.00 BSC	
e	1.00 BSC	
S	0.50 BSC	

Figure 7. 256 MAPBGA Package Outline

6.4 Package Dimensions—160 QFP

Figure 9 shows MCF5232CAB80 package dimensions.





DETAIL C

NOTES

1. DIMENSIONING AND TOLERINCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER
3. DATUM PLAN -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
4. DATUMS -A-, -B-, AND -D- TO BE DETERMINED AT DATUM PLANE -H-.
5. DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE -C-.
6. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	27.90	28.10	1.098	1.106
B	27.90	28.10	1.098	1.106
C	3.35	3.85	0.132	1.106
D	0.22	0.38	0.009	0.015
E	3.20	3.50	0.126	0.138
F	0.22	0.33	0.009	0.013
G	0.65 BSC		0.026 REF	
H	0.25	0.35	0.010	0.014
J	0.11	0.23	0.004	0.009
K	0.70	0.90	0.028	0.035
L	25.35 BSC		0.998 REF	
M	5°	16°	5°	16°
N	0.11	0.19	0.004	0.007
P	0.325 BSC		0.013 REF	
Q	0°	7°	0°	7°
R	0.13	0.30	0.005	0.012
S	31.00	31.40	1.220	1.236
T	0.13	—	0.005	—
U	0°	—	0°	—
V	31.00	31.40	1.220	1.236
W	0.4	—	0.016	—
X	1.60 REF		0.063 REF	
Y	1.33 REF		0.052 REF	
Z	1.33 REF		0.052 REF	

Case 864A-03

Figure 9. 160 QFP Package Dimensions

The average chip-junction temperature (T_J) in °C can be obtained from:

$$T_J = T_A + (P_D \times \Theta_{JMA}) \quad (1)$$

Where:

T_A= Ambient Temperature, °C

Θ_{JMA}= Package Thermal Resistance, Junction-to-Ambient, °C/W

P_D= P_{INT} + $P_{I/O}$

P_{INT}= $I_{DD} \times V_{DD}$, Watts - Chip Internal Power

$P_{I/O}$= Power Dissipation on Input and Output Pins — User Determined

For most applications $P_{I/O} < P_{INT}$ and can be ignored. An approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected) is:

$$P_D = K \div (T_J + 273°C) \quad (2)$$

Solving equations 1 and 2 for K gives:

$$K = P_D \times (T_A + 273\ °C) + \Theta_{JMA} \times P_D{}^2 \quad (3)$$

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A. Using this value of K, the values of P_D and T_J can be obtained by solving equations (1) and (2) iteratively for any value of T_A.

7.3 DC Electrical Specifications

Table 9. DC Electrical Specifications[1]

Characteristic	Symbol	Min	Typical	Max	Unit
Core Supply Voltage	V_{DD}	1.4	—	1.6	V
Pad Supply Voltage	OV_{DD}	3.0	—	3.6	V
PLL Supply Voltage	V_{DDPLL}	3.0	—	3.6	V
Input High Voltage	V_{IH}	$0.7 \times OV_{DD}$	—	3.65	V
Input Low Voltage	V_{IL}	$V_{SS} - 0.3$	—	$0.35 \times OV_{DD}$	V
Input Hysteresis	V_{HYS}	$0.06 \times OV_{DD}$	—	—	mV
Input Leakage Current $V_{in} = V_{DD}$ or V_{SS}, Input-only pins	I_{in}	–1.0	—	1.0	μA
High Impedance (Off-State) Leakage Current $V_{in} = V_{DD}$ or V_{SS}, All input/output and output pins	I_{OZ}	–1.0	—	1.0	μA
Output High Voltage (All input/output and all output pins) I_{OH} = –5.0 mA	V_{OH}	OV_{DD} - 0.5	—	—	V
Output Low Voltage (All input/output and all output pins) I_{OL} = 5.0mA	V_{OL}	—	—	0.5	V
Weak Internal Pull Up Device Current, tested at V_{IL} Max.[2]	I_{APU}	–10	—	– 130	μA

7.4 Oscillator and PLLMRFM Electrical Characteristics

Table 10. HiP7 PLLMRFM Electrical Specifications[1]

Num	Characteristic	Symbol	Min. Value	Max. Value	Unit
1	PLL Reference Frequency Range Crystal reference External reference 1:1 mode (NOTE: $f_{sys/2} = 2 \times f_{ref\_1:1}$)	 $f_{ref\_crystal}$ f_{ref_ext} $f_{ref\_1:1}$	 8 8 24	 25 25 75	MHz
2	Core frequency CLKOUT Frequency [2] External reference On-Chip PLL Frequency	f_{sys} $f_{sys/2}$	 0 $f_{ref} \div 32$	150 75 75	MHz MHz MHz
3	Loss of Reference Frequency [3, 5]	f_{LOR}	100	1000	kHz
4	Self Clocked Mode Frequency [4, 5]	f_{SCM}	10.25	15.25	MHz
5	Crystal Start-up Time [5, 6]	t_{cst}	—	10	ms
6	XTAL Load Capacitance[5]		5	30	pF
7	PLL Lock Time [5, 7,13]	t_{lpll}	—	750	µs
8	Power-up To Lock Time [5, 6,8] With Crystal Reference (includes 5 time) Without Crystal Reference[9]	t_{lplk}	 — —	 11 750	 ms µs
9	1:1 Mode Clock Skew (between CLKOUT and EXTAL) [10]	t_{skew}	–1	1	ns
10	Duty Cycle of reference [5]	t_{dc}	40	60	%
11	Frequency un-LOCK Range	f_{UL}	–3.8	4.1	% $f_{sys/2}$
12	Frequency LOCK Range	f_{LCK}	–1.7	2.0	% $f_{sys/2}$
13	CLKOUT Period Jitter, [5, 6, 8,11, 12] Measured at $f_{sys/2}$ Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval)	C_{jitter}	 — —	 5.0 .01	% $f_{sys/2}$
14	Frequency Modulation Range Limit[13,14] ($f_{sys/2}$ Max must not be exceeded)	C_{mod}	0.8	2.2	%$f_{sys/2}$
15	ICO Frequency. $f_{ico} = f_{ref} \times 2 \times (MFD+2)$ [15]	f_{ico}	48	150	MHz

1 All values given are initial design targets and subject to change.
2 All internal registers retain data at 0 Hz.
3 “Loss of Reference Frequency” is the reference frequency detected internally, which transitions the PLL into self clocked mode.
4 Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below f_{LOR} with default MFD/RFD settings.
5 This parameter is guaranteed by characterization before qualification rather than 100% tested.
6 Proper PC board layout procedures must be followed to achieve specifications.

7 This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).

8 Assuming a reference is available at power up, lock time is measured from the time V_{DD} and V_{DDSYN} are valid to $\overline{\text{RSTOUT}}$ negating. If the crystal oscillator is being used as the reference for the PLL, then the crystal start up time must be added to the PLL lock time to determine the total start-up time.

9 $t_{lpll} = (64 * 4 * 5 + 5 \times \tau) \times T_{ref}$, where $T_{ref} = 1/F_{ref\_crystal} = 1/F_{ref\_ext} = 1/F_{ref\_1:1}$, and $\tau = 1.57x10^{-6} \times 2(MFD + 2)$.

10 PLL is operating in 1:1 PLL mode.

11 Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum $f_{sys/2}$. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDSYN} and V_{SSSYN} and variation in crystal oscillator frequency increase the Cjitter percentage for a given interval.

12 Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of Cjitter+Cmod.

13 Modulation percentage applies over an interval of 10μs, or equivalently the modulation rate is 100KHz.

14 Modulation rate selected must not result in $f_{sys/2}$ value greater than the $f_{sys/2}$ maximum specified value. Modulation range determined by hardware design.

15 $f_{sys/2} = f_{ico} / (2 * 2^{RFD})$

7.5 External Interface Timing Characteristics

Table 11 lists processor bus input timings.

NOTE

All processor bus timings are synchronous; that is, input setup/hold and output delay with respect to the rising edge of a reference clock. The reference clock is the CLKOUT output.

All other timing relationships can be derived from these values.

Table 11. Processor Bus Input Timing Specifications

Name	Characteristic[1]	Symbol	Min	Max	Unit
freq	System bus frequency	$f_{sys/2}$	50	75	MHz
B0	CLKOUT period	t_{cyc}	—	1/75	ns
Control Inputs					
B1a	Control input valid to CLKOUT high[2]	t_{CVCH}	9	—	ns
B1b	$\overline{\text{BKPT}}$ valid to CLKOUT high[3]	t_{BKVCH}	9	—	ns
B2a	CLKOUT high to control inputs invalid[2]	t_{CHCII}	0	—	ns
B2b	CLKOUT high to asynchronous control input $\overline{\text{BKPT}}$ invalid[3]	t_{BKNCH}	0	—	ns
Data Inputs					
B4	Data input (D[31:0]) valid to CLKOUT high	t_{DIVCH}	4	—	ns
B5	CLKOUT high to data input (D[31:0]) invalid	t_{CHDII}	0	—	ns

1 Timing specifications are tested using full drive strength pad configurations in a 50ohm transmission line environment..

2 $\overline{\text{TEA}}$ and $\overline{\text{TA}}$ pins are being referred to as control inputs.

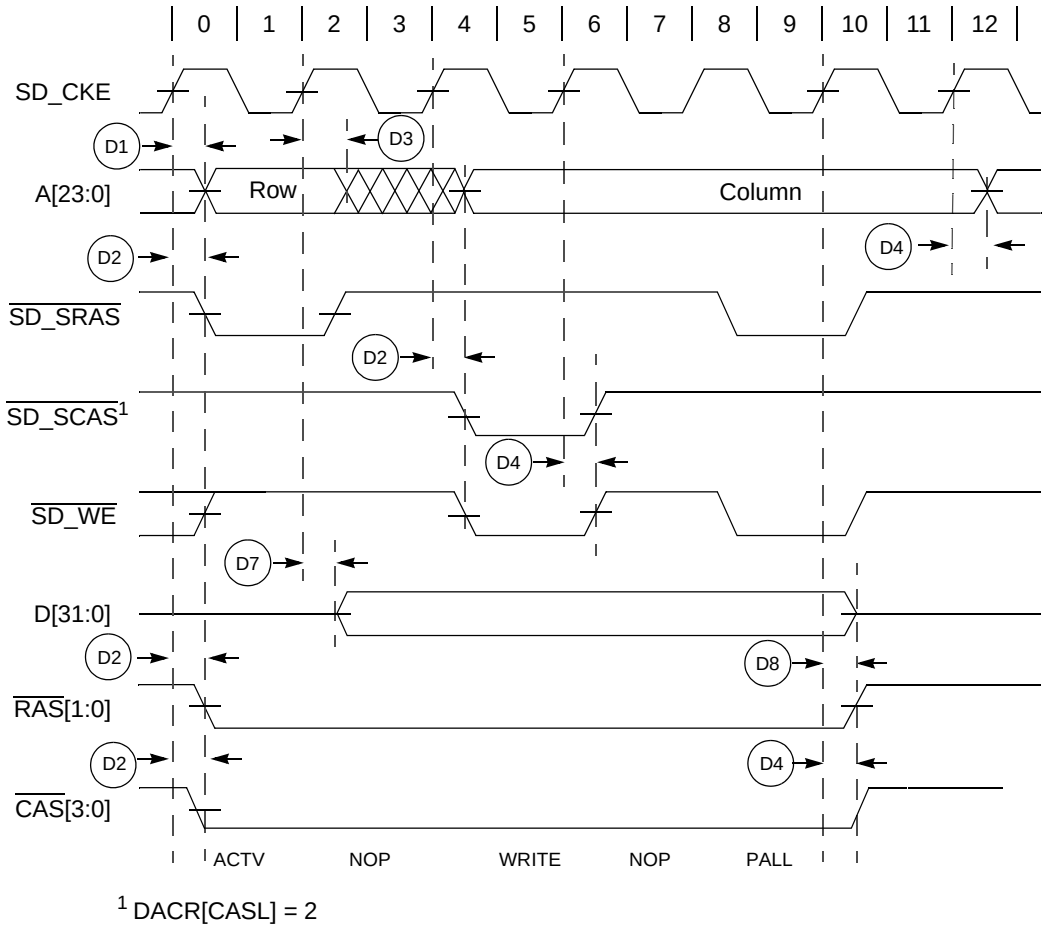
3 Refer to figure A-19.

Table 12. External Bus Output Timing Specifications (continued)

Name	Characteristic	Symbol	Min	Max	Unit
Address and Attribute Outputs					
B8	CLKOUT high to address (A[23:0]) and control ($\overline{TS}$, $\overline{TSIZ}$[1:0], $\overline{TIP}$, R/$\overline{W}$) valid	t_{CHAV}	—	9	ns
B9	CLKOUT high to address (A[23:0]) and control ($\overline{TS}$, $\overline{TSIZ}$[1:0], $\overline{TIP}$, R/$\overline{W}$) invalid	t_{CHAI}	1.5	—	ns
Data Outputs					
B11	CLKOUT high to data output (D[31:0]) valid	t_{CHDOV}	—	9	ns
B12	CLKOUT high to data output (D[31:0]) invalid	t_{CHDOI}	1.5	—	ns
B13	CLKOUT high to data output (D[31:0]) high impedance	t_{CHDOZ}	—	9	ns

1 $\overline{CS}$ transitions after the falling edge of CLKOUT.
2 $\overline{BS}$ transitions after the falling edge of CLKOUT.
3 $\overline{OE}$ transitions after the falling edge of CLKOUT.

Figure 15 shows an SDRAM write cycle.



[1] DACR[CASL] = 2

Figure 15. SDRAM Write Cycle

7.7 General Purpose I/O Timing

Table 14. GPIO Timing[1]

NUM	Characteristic	Symbol	Min	Max	Unit
G1	CLKOUT High to GPIO Output Valid	t_{CHPOV}	—	10	ns
G2	CLKOUT High to GPIO Output Invalid	t_{CHPOI}	1.5	—	ns
G3	GPIO Input Valid to CLKOUT High	t_{PVCH}	9	—	ns
G4	CLKOUT High to GPIO Input Invalid	t_{CHPI}	1.5	—	ns

[1] GPIO pins include: INT, ETPU, UART, FlexCAN, Timer, $\overline{\text{DREQ}n}$ and $\overline{\text{DACK}n}$ pins.

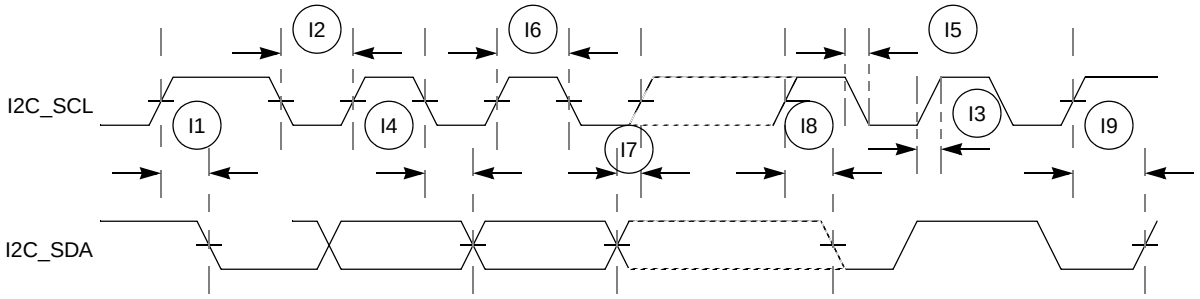


Figure 18. I²C Input/Output Timings

7.10 Fast Ethernet AC Timing Specifications

MII signals use TTL signal levels compatible with devices operating at either 5.0 V or 3.3 V.

7.10.1 MII Receive Signal Timing (ERXD[3:0], ERXDV, ERXER, and ERXCLK)

The receiver functions correctly up to a ERXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ERXCLK frequency.

Table 18 lists MII receive channel timings.

Table 18. MII Receive Signal Timing

Num	Characteristic	Min	Max	Unit
M1	ERXD[3:0], ERXDV, ERXER to ERXCLK setup	5	—	ns
M2	ERXCLK to ERXD[3:0], ERXDV, ERXER hold	5	—	ns
M3	ERXCLK pulse width high	35%	65%	ERXCLK period
M4	ERXCLK pulse width low	35%	65%	ERXCLK period

Figure 19 shows MII receive signal timings listed in Table 18.

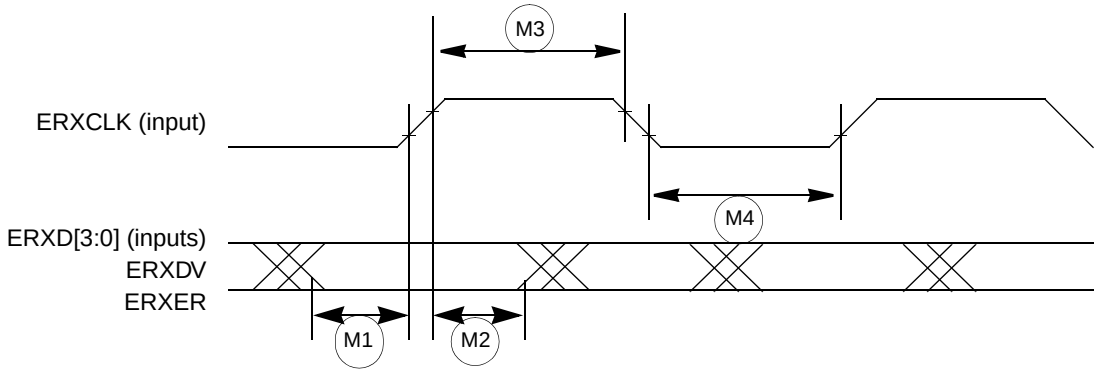


Figure 19. MII Receive Signal Timing Diagram

7.13 JTAG and Boundary Scan Timing

Table 24. JTAG and Boundary Scan Timing

Num	Characteristics[1]	Symbol	Min	Max	Unit
J1	TCLK Frequency of Operation	f_{JCYC}	DC	1/4	$f_{sys/2}$
J2	TCLK Cycle Period	t_{JCYC}	4	—	t_{CYC}
J3	TCLK Clock Pulse Width	t_{JCW}	26	—	ns
J4	TCLK Rise and Fall Times	t_{JCRF}	0	3	ns
J5	Boundary Scan Input Data Setup Time to TCLK Rise	t_{BSDST}	4	—	ns
J6	Boundary Scan Input Data Hold Time after TCLK Rise	t_{BSDHT}	26	—	ns
J7	TCLK Low to Boundary Scan Output Data Valid	t_{BSDV}	0	33	ns
J8	TCLK Low to Boundary Scan Output High Z	t_{BSDZ}	0	33	ns
J9	TMS, TDI Input Data Setup Time to TCLK Rise	t_{TAPBST}	4	—	ns
J10	TMS, TDI Input Data Hold Time after TCLK Rise	t_{TAPBHT}	10	—	ns
J11	TCLK Low to TDO Data Valid	t_{TDODV}	0	26	ns
J12	TCLK Low to TDO High Z	t_{TDODZ}	0	8	ns
J13	$\overline{\text{TRST}}$ Assert Time	t_{TRSTAT}	100	—	ns
J14	$\overline{\text{TRST}}$ Setup Time (Negation) to TCLK High	t_{TRSTST}	10	—	ns

1 JTAG_EN is expected to be a static signal. Hence, specific timing is not associated with it.

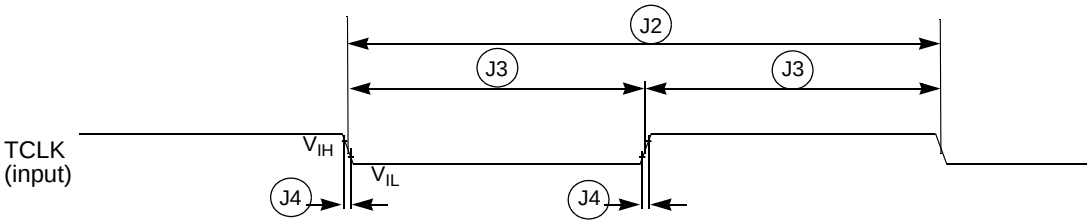


Figure 24. Test Clock Input Timing

7.14 Debug AC Timing Specifications

Table 25 lists specifications for the debug AC timing parameters shown in Figure 29.

Table 25. Debug AC Timing Specification

Num	Characteristic	150 MHz		Units
		Min	Max	
DE0	PSTCLK cycle time	—	0.5	t_{cyc}
DE1	PST valid to PSTCLK high	4	—	ns
DE2	PSTCLK high to PST invalid	1.5	—	ns
DE3	DSCLK cycle time	5	—	t_{cyc}
DE4	DSI valid to DSCLK high	1	—	t_{cyc}
DE5[1]	DSCLK high to DSO invalid	4	—	t_{cyc}
DE6	$\overline{\text{BKPT}}$ input data setup time to CLKOUT rise	4	—	ns
DE7	CLKOUT high to $\overline{\text{BKPT}}$ high Z	0	10	ns

1 DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 28 shows real-time trace timing for the values in Table 25.

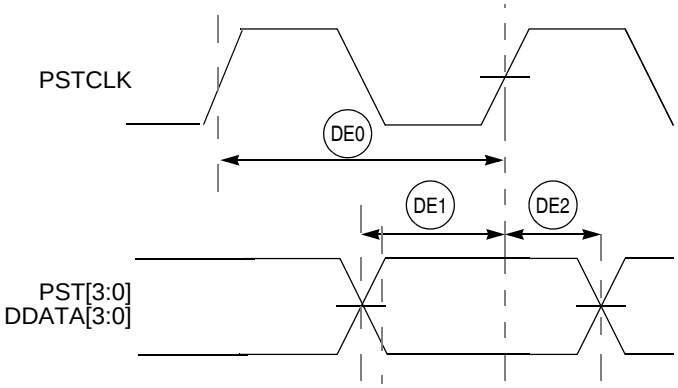


Figure 28. Real-Time Trace AC Timing

Figure 29 shows BDM serial port AC timing for the values in Table 25.

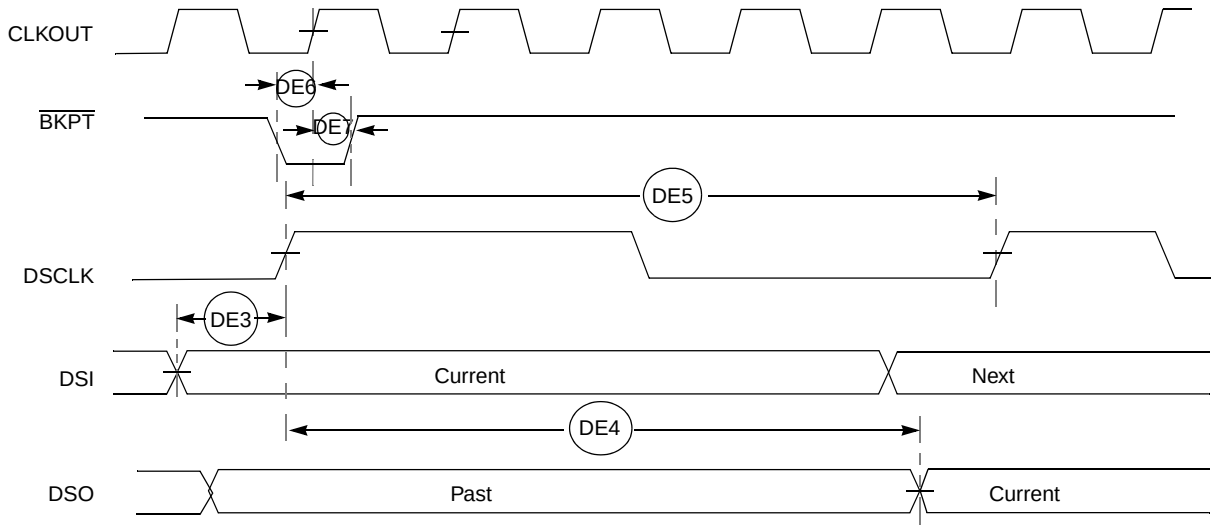


Figure 29. BDM Serial Port AC Timing

8 Documentation

Documentation regarding the MCF523*x* and their development support tools is available from a local Freescale distributor, a Freescale semiconductor sales office, the Freescale Literature Distribution Center, or through the Freescale web address at http://www.freescale.com/coldfire.

9 Document Revision History

The below table provides a revision history for this document.

Table 26. MCF5235EC Revision History

Rev. No.	Substantive Change(s)
0	Preliminary release.
1	• Updated Signal List table
1.1	• Removed duplicate information in the module description sections. The information is all in the Signals Description Table.
1.2	• Corrected Figure 8 pin 81. VDD instead of VSS • Changed instances of Motorola to Freescale
1.3	• Removed detailed signal description section. This information can be found in the MCF5235RM Chapter 2. • Removed detailed feature list. This information can be found in the MCF5235RM Chapter 1. • Corrected Figure 2 pin F10. VSS instead of VDD. Change made in Table 2 as well. • Corrected Figure 8 pin 81. OVDD instead of VDD. Change made in Table 2 as well. • Cleaned up many inconsistencies within the pinout figure signal names • Corrected document IDs in Documentation Table
1.4	• Added values for ‘Maximum operating junction temperature’ in Table 8. • Added typical values for ‘Core operating supply current (master mode)’ in Table 9. • Added typical values for ‘Pad operating supply current (master mode)’ in Table 9. • Removed unnecessary PLL specifications, #6-9, in Table 10.

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